

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



Applicants : Hiroyuki KIKUCHI et al.

Group Art Unit: 2852

Appln. No. : 10/599,698  
(National Stage of PCT/JP2004/007971)

Examiner: Not Yet Assigned

I.A. Filed : July 8, 2004

Confirmation No. 2938

For : IMAGE SENSOR TEST EQUIPMENT

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
U.S. Patent and Trademark Office  
Customer Service Window, Mail Stop Amendment  
Randolph Building  
401 Dulany Street  
Alexandria, VA 22314

Sir:

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and §§1.97-1.98, Applicants hereby bring to the attention of the Examiner the following information.

The following documents were cited in an International Search Report with respect to International Patent Application No. PCT/JP2004/007971, of which the present application is the U.S. National Stage Application. A copy of the International Search Report has been filed concurrently with the present application and should thus have been brought to the attention of the Examiner.

- (1) Japanese Laid-Open Patent Publication No. HEI 11-284034 A, together  
with an English language Abstract of the same;

- (2) Japanese Laid-Open Patent Publication No. 2002-267571 A, together with an English language Abstract of the same;
- (3) Japanese Laid-Open Patent Publication No. HEI 6-241746 A, together with an English language Abstract of the same;
- (4) Japanese Laid-Open Patent Publication No. 2003-282642 A, together with an English language Abstract of the same; and
- (5) Japanese Laid-Open Patent Publication No. HEI 5-17025 A, together with an English language Abstract of the same.

The relevance of the documents cited in the International Search Report, as ascertained with respect to the International claims by the International Examiner, is set forth in the International Search Report.

Applicants further submits the following document:

- (6) U.S. Patent Application No. 10/599,374 to KIYOKAWA et al., which was filed on September 27, 2006.

Further to the U.S. Patent and Trademark Office's decision to waive the requirement under 37 C.F.R. §1.98 (a)(2)(iii) if the U.S. patent application was filed after June 30, 2003, a copy of the U.S. patent application is not enclosed herewith. However, if a copy is needed, the Examiner is respectfully requested to contact the undersigned.

Also, when the above-noted pending application is published, the Examiner is respectfully requested to list its publication number on a PTO 1449 Form (or PTO 892 Form) to confirm consideration thereof.

Applicants respectfully request that the Examiner consider the above material and cite the same. Copies of above-noted Japanese, including the noted English

P30902.A02

language Abstracts, are attached hereto, and all of the documents are listed on an attached PTO-1449 Form. The Examiner is requested to initial the appropriate spaces on the attached Form and to return a copy of the completed Form to Applicants with the next official communication in the present application.

Should the Examiner have any questions, the Examiner is invited to contact the undersigned at the below-listed telephone number.

Respectfully submitted,  
Hiroyuki KIKUCHI et al.



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William S. Boshnick  
Reg. No. 44,550

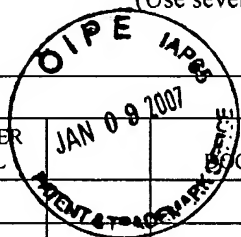
January 8, 2007  
GREENBLUM & BERNSTEIN, P.L.C.  
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(Use several sheets if necessary)

Applicant  
Hiroyuki KIKUCHI et al. ☐

Filing Date  
July 8, 2004

Group 2852	
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## U.S. PATENT DOCUMENTS

[illegible]

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	11	- 2 8 2 0 3 4	10/15/99	JAPAN			
	2002	- 2 6 7 5 7 1	09/18/02	JAPAN			
	6	- 2 4 1 7 4 6	09/02/94	JAPAN			
	2003	- 2 8 2 6 4 2	10/03/03	JAPAN			
	5	- 1 7 0 2 5	01/26/93	JAPAN			

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	1	English language Abstract of JP 11-282034.
	2	U.S. Patent Application No. 10/599,374 to KIYOKAWA et al., which was filed on September 27, 2006.
	3	English language Abstract of JP 2002-267571.
	4	English language Abstract of JP 6-241746.
	5	English language Abstract of JP 2003-282642.
	6	English language Abstract of JP 5-17025

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.